

● General Description

This silicon carbide Power MOSFET device has been developed using ZMJ’s advanced 2nd generation SiC MOSFET technology. The device features a very low $R_{DS(on)}$ over the entire temperature range combined with low capacitances and very high switching operations. It improves application performance in frequency, energy efficiency, system size and weight reduction.

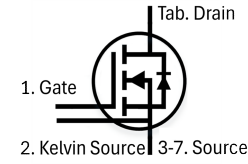
● Features

- High Blocking Voltage
- High Speed Switching With Low Capacitances
- Low $R_{DS(ON)}$ to Minimize Conductive Loss
- Low Gate Charge For Fast Switching
- Low Thermal Resistance
- 100% Avalanche Tested
- AEC-Q101 Qualified

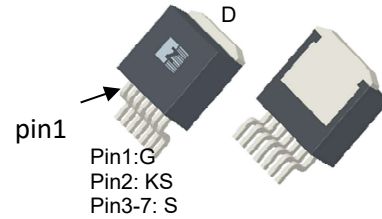
● Application

- Motor Drives
- On Board Charger
- DC-DC
- Auxiliary Drives

● Product Summary



$V_{DS} = 1200V$
 $R_{DS(ON)} = 49m\Omega$
 $I_D = 37A$



TO-263-7



● Ordering Information:

Part NO.	ZMCA060N120B7
Marking	ZMC060N120
Packing Information	REEL TAPE
Basic Ordering Unit (pcs)	800

● Absolute Maximum Ratings ($T_C=25^\circ C$)

Parameter	Symbol	Conditions	Value	Unit
Drain-Source Voltage	V_{DS}		1200	V
Gate-Source Voltage	V_{GS}	Transient Voltage	-10V/25V	V
	V_{GS}	Static Voltage	-10V/24V	V
Recommended Turn On Gate Voltage	$V_{GS(on)}$		15 to 18V	V
Recommended Turn Off Gate Voltage	$V_{GS(off)}$		-4V to 0V	V
Continuous Drain Current	I_D	$T_C=25^\circ C$	37	A
	I_D	$T_C=75^\circ C$	30	A
	I_D	$T_C=100^\circ C$	26	A

1200V N-Channel SiC MOSFET

Pulsed Drain Current ^①	I_{DM}	Pulsed; $t_p \leq 10 \mu s$; $T_{mb} = 25^\circ C$;	148	A
Total Power Dissipation	P_D	$T_C = 25^\circ C$	224	W
Total Power Dissipation	P_D	$T_A = 25^\circ C$	2.4	W
Operating Junction Temperature	T_J		-55 to +175	$^\circ C$
Storage Temperature	T_{STG}		-55 to +175	$^\circ C$
Single Pulse Avalanche Energy	E_{AS}	$L=0.5mH, V_{GS}=18V, R_g=25\Omega$	256	mJ
ESD Level (HBM)			Class2	

• Thermal Resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction - Case	R_{thJC}	-	-	0.67	$^\circ C/W$
Thermal Resistance, Junction-Ambient	$R_{thJA\oplus}$	-	-	62	$^\circ C/W$
Soldering Temperature(total time<10s)	T_{sold}	-	-	260	$^\circ C$

• Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	1200	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 5mA$	2	2.9	4	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS} = 0V, V_{DS} = 1200V$	-	-	10	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS} = -10V, V_{DS} = 0V$	-	-	-100	nA
		$V_{GS} = 25V, V_{DS} = 0V$	-	-	100	nA
Static Drain-Source On Resistance	$R_{DS(on)}$	$T_J = 25^\circ C, V_{GS} = 18V, I_D = 20A$	-	49	65	m Ω
		$T_J = 175^\circ C, V_{GS} = 18V, I_D = 20A$	-	98	-	m Ω
		$T_J = 25^\circ C, V_{GS} = 15V, I_D = 20A$	-	59	-	m Ω
Forward Transconductance	g_{fs}	$V_{DS} = 10V, I_{SD} = 20A$	-	8.5	-	S
Diode Forward Voltage	V_{FSD}	$V_{GS} = -4V, I_{SD} = 20A$	-	4.2	5	V

• Dynamic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input Capacitance	C_{iss}	$f = 100KHz, V_{DS} = 800V$	-	1578	-	pF
Output Capacitance	C_{oss}		-	67	-	
Reverse Transfer Capacitance	C_{rss}		-	3	-	
Output Charge	Q_{oss}	$f = 100KHz, V_{GS} = 0V, V_{DS} = 0V \text{ to } 800V$	-	94	-	nC
Coss Stored Energy	E_{oss}		-	25	-	μJ
Gate Resistance	R_g	$f = 1MHz$	-	1.7	-	Ω
Total Gate Charge	Q_g	$V_{DD} = 800V, I_D = 20A, V_{GS} = -4V/18V$	-	69	-	nC
Gate - Source Charge	Q_{gs}		-	19	-	
Gate - Drain Charge	Q_{gd}		-	24	-	

Turn-ON Delay Time	$t_{D(on)}$	$V_{GS}=-4V/18V, V_{DS}=800V,$ $R_G=10\Omega, I_D=20A,$ $L=505\mu H$	-	13	-	ns
Turn-ON Rise Time	t_r		-	3.4	-	ns
Turn-Off Delay Time	$t_{D(off)}$		-	36	-	ns
Turn-Off Fall Time	t_f		-	15	-	ns
Turn-On Energy	E_{on}		-	527	-	uJ
Turn-Off Energy	E_{off}		-	153	-	uJ
Reverse Recovery Time	t_{rr}	$V_{DD}=800V, di_S/dt =$ $600A/\mu s, I_S=20A$	-	25	-	ns
Reverse Recovery Peak Current	I_{rrm}		-	5.8	-	A
Reverse Recovery Charge	Q_{rr}		-	82	-	nC

● Characteristics Diagrams

Fig.1 Gate-Charge Characteristics

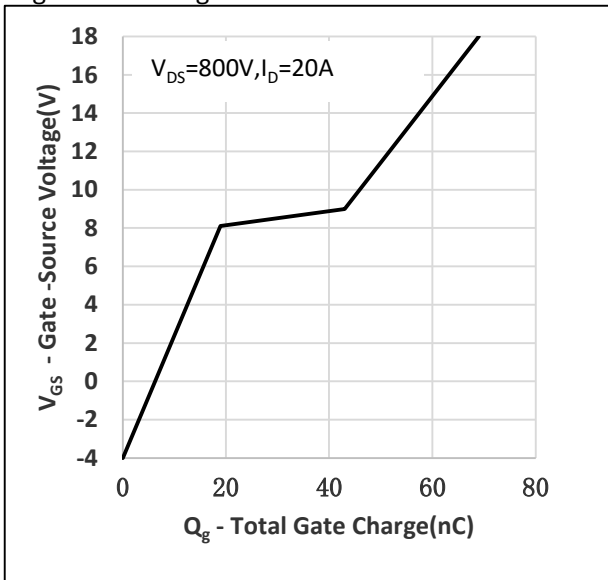


Fig.2 Capacitance Characteristics

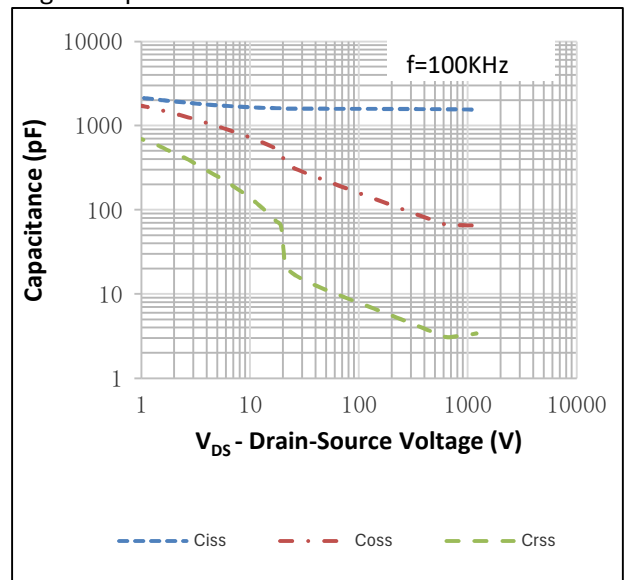


Fig.3 Power Dissipation

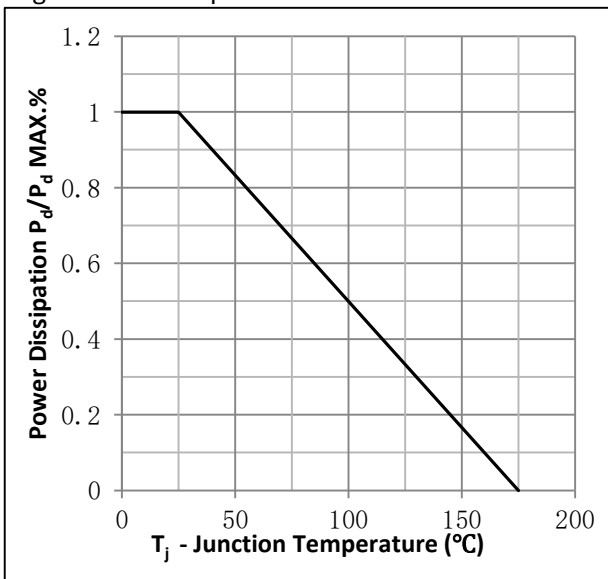


Fig.4 Typical Output Characteristics

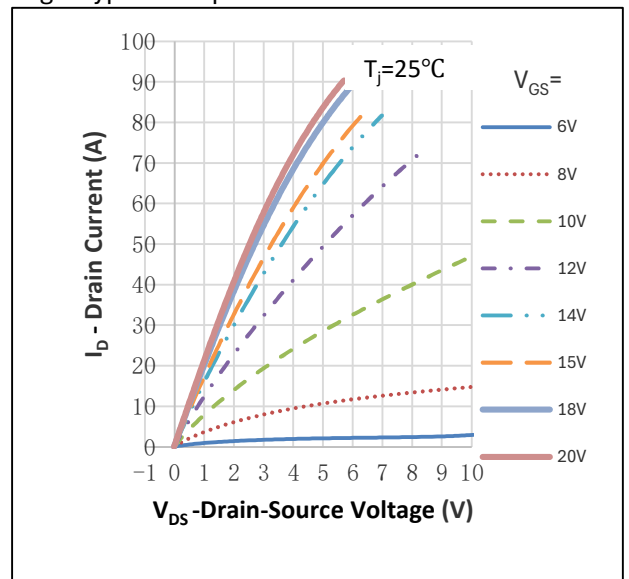


Fig.5 Threshold Voltage vs. Junction Temperature

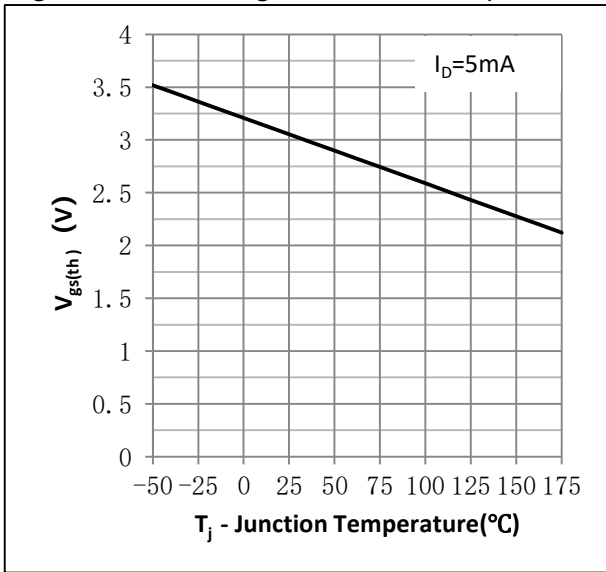


Fig.6 On-Resistance vs. Drain Current

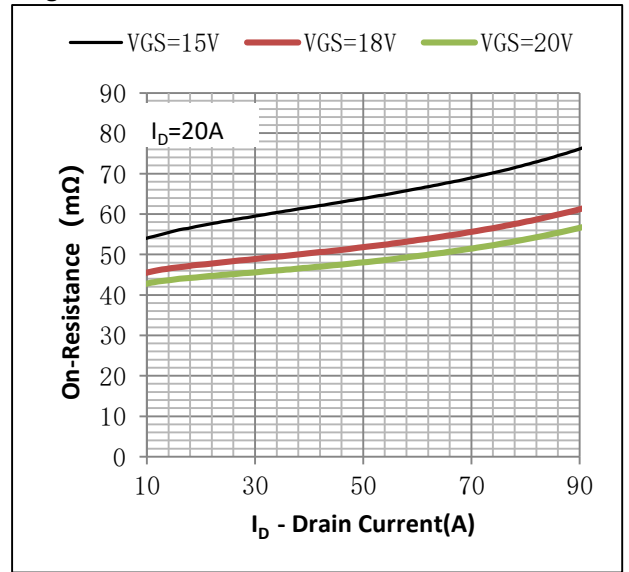


Fig.7 On-Resistance vs. Gate Source Voltage

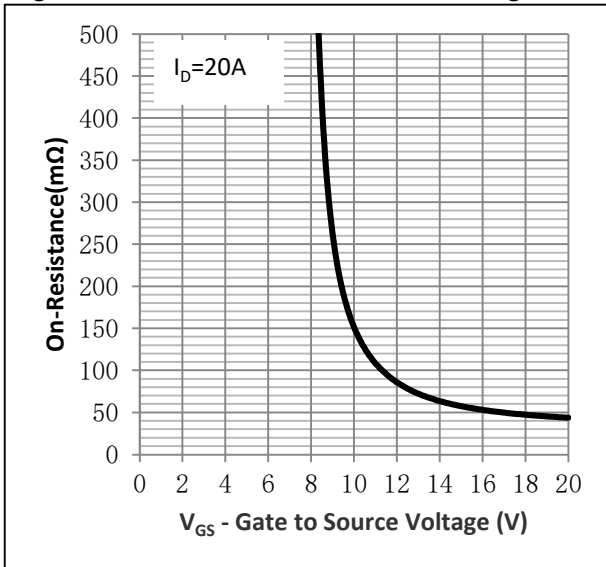


Fig.8 On-Resistance vs. Junction Temperature

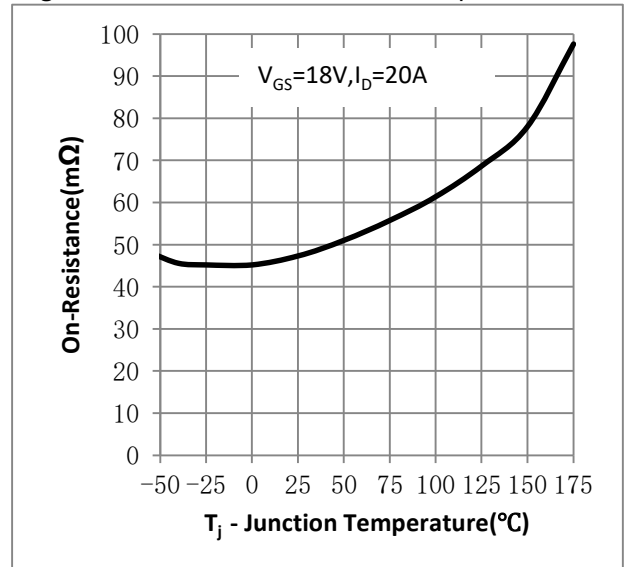


Figure 9. Diode Forward Voltage vs. Current

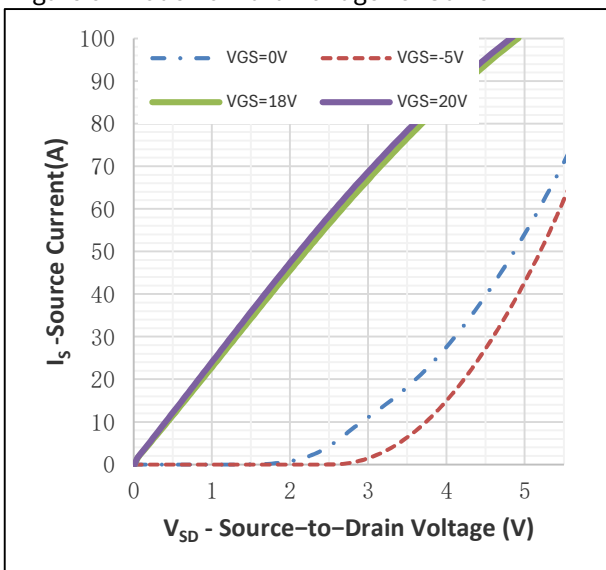


Figure 10. Transfer Characteristics

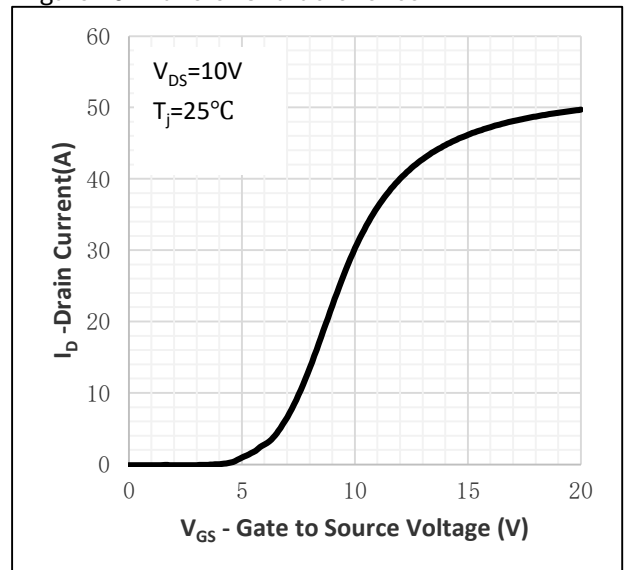


Fig.11 SOA Maximum Safe Operating Area

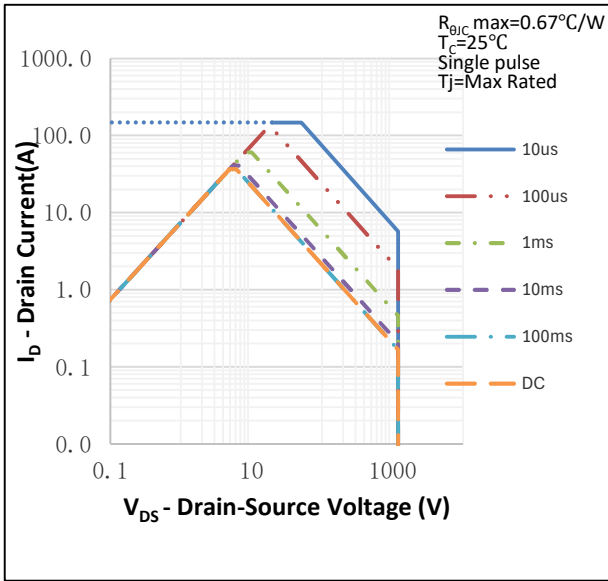


Fig.12 I_D vs. Junction Temperature②

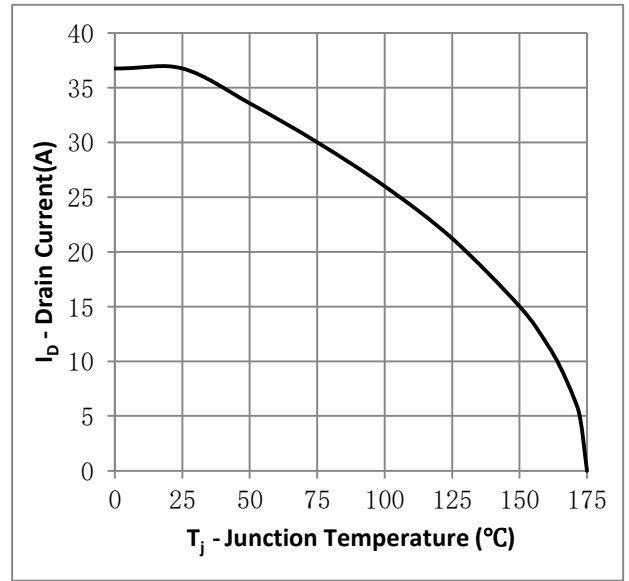


Fig.13 Output Capacitor Stored Energy

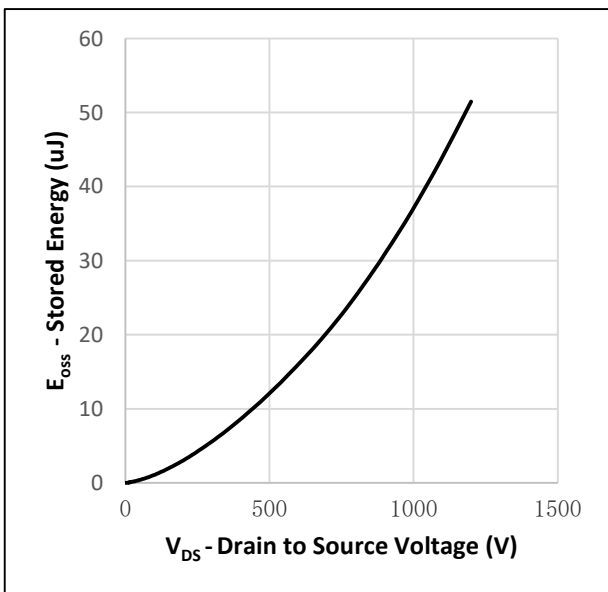
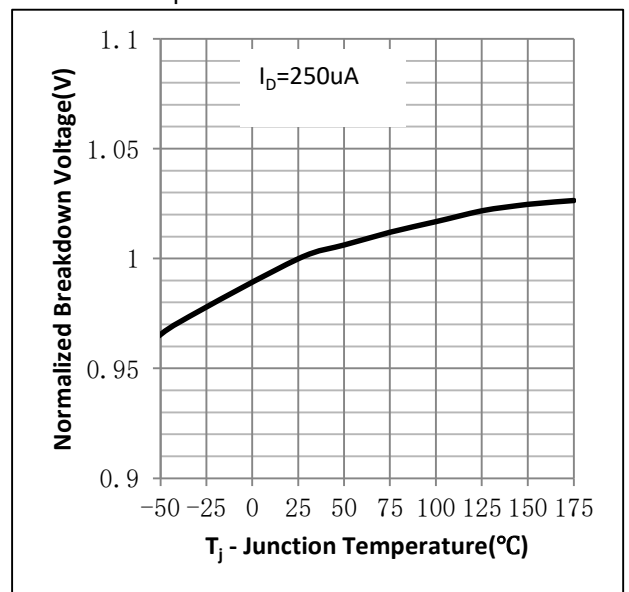
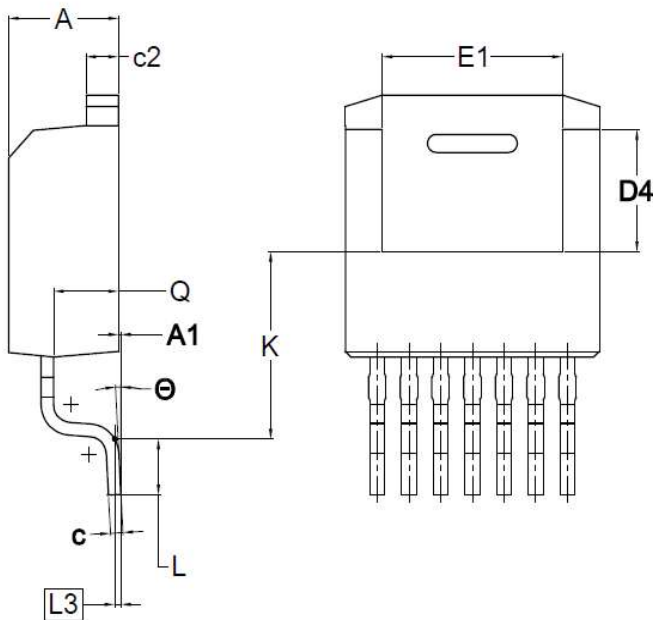
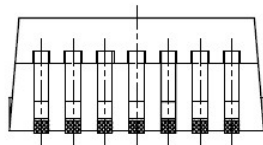
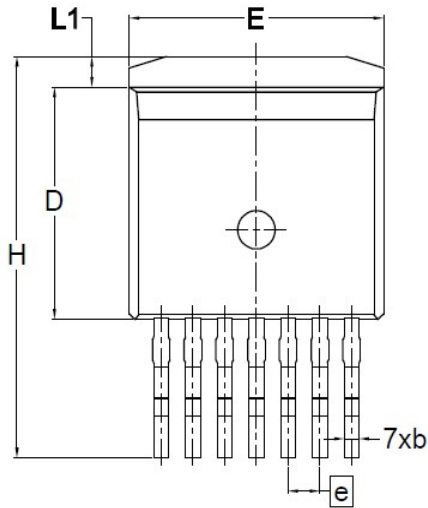


Fig.14 Normalized Breakdown Voltage vs. Junction Temperature



•TO-263-7 Package Outline



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	4.30	4.40	4.50
A1	0.00	0.10	0.25
b	0.50	0.60	0.70
c	0.45	0.50	0.60
c2	1.20	1.30	1.40
D	8.93	9.08	9.23
D4	4.65	4.80	4.95
E	10.08	10.18	10.28
E1	6.82	7.22	7.62
e	1.27 BSC		
H	15.00	15.70	16.00
K	7.30		
L	1.90	2.20	2.50
L1	1.00	1.20	1.40
L3	0.25 BSC		
Q	2.45	2.60	2.75
Θ	0°	3°	7°



Note:

- ① The value of $R\theta JA$ is measured with the device in a still environment with $T_A=25^\circ C$
- ② Practically the current will be limited by PCB, thermal design and operating temperature. $V_{GS}=18V$.

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Revision History:

Version	Date	Change
A	2024/7/1	New
B	2024/11/22	Update VGS maximum rating and IGSS+ test condition.